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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/757,175	01/09/2001	Pang-Chia Lu	10234-2	1308
23455	7590	06/27/2006	EXAMINER	
EXXONMOBIL CHEMICAL COMPANY 5200 BAYWAY DRIVE P.O. BOX 2149 BAYTOWN, TX 77522-2149			CHANG, VICTOR S	
		ART UNIT	PAPER NUMBER	
		1771		

DATE MAILED: 06/27/2006

Please find below and/or attached an Office communication concerning this application or proceeding.



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APPLICATION NO./ CONTROL NO.	FILING DATE	FIRST NAMED INVENTOR / PATENT IN REEXAMINATION	ATTORNEY DOCKET NO.
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EXAMINER

ART UNIT PAPER

20060620

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Commissioner for Patents

In view of the full translation, copies of JAP and Derwent Abstract are no longer needed for the Office action mailed 6/14/2006, and have not been provided in the PTO-892 form. It is noted that in the heading of section 5 of the Office action the relied upon reference JP 04-367449 has been properly switched to the full English translation, instead of Patent Abstract of Japan (JAP) and Derwent Abstract. For the headings in sections 6 and 7, however, the changes were inadvertently not made. Nevertheless, the body of each of sections 6 and 7 has clearly indicated that the same teachings of the full English translation are relied upon, and the Examiner wish to clarify that in fact the same reference (translation) are relied upon, the JAP and Derwent Abstract should be ignored. If Applicants have further questions about the references being applied, please contact the Examiner for an interview.

Vuer-Chauq
Examiner
AU 1771